

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/754,594	ONO ET AL.	
Examiner	Art Unit	
Kin-Chan Chen	1765	

SEARCHED						
Class	Subclass	Date	Examiner			
438	706	9/7/05	Ka			
438	710					
438	714					
438	723					
15-6	345					
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Keywords search USPBT, USPG-pub. Epo, JPO, Derwent 78M-TDR inventor search	9/1/2	kec		
peruse parent applications	9/7/-	Kcc		
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